

Socket for testing an electrical component

Abstract

The embodiments of the present application provide a socket for testing an electrical component, which comprises: a socket body, inside which a probe receiving hole is provided; a contact probe, which is received in the probe receiving hole, wherein one end of the contact probe is provided with a plunger, one end of the plunger is provided with a protrusion; and a flexible plate, which is provided on one side of the socket body for contact with a second electrical component, wherein the flexible plate includes an insulation layer and a through-electrode installed on the insulation layer, and wherein one end of the through-electrode is configured to contact the second electrical component, and the other end of the through-electrode is configured to contact the one end of the plunger; wherein, in the case that the through-electrode contacts the one end of the plunger, the through-electrode is at least not in contact with the top of the protrusion.

Fig. 1